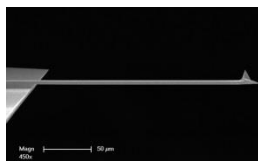
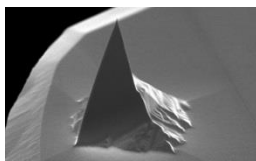
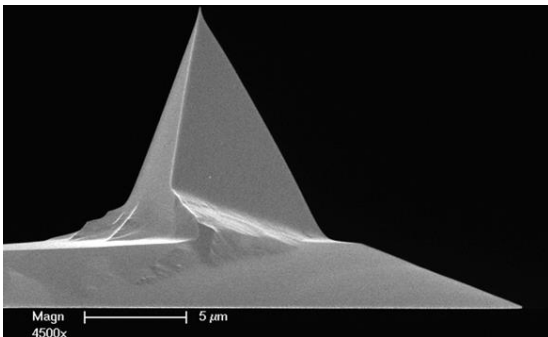


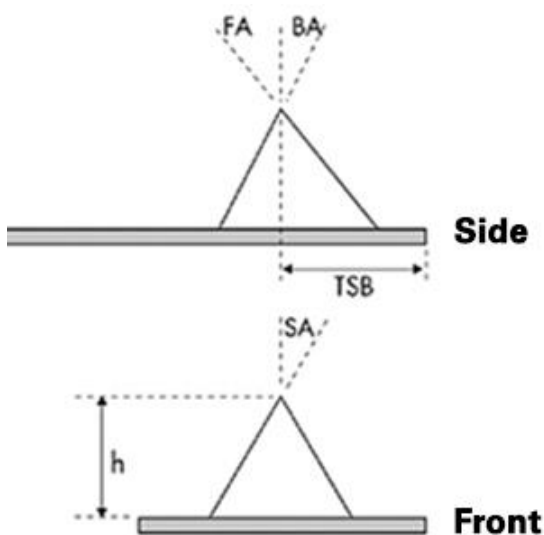
FMV

Soft Tapping,
Non-Contact AFM Probes



Models

10-Pack No Reflex Coating	Wafer No Reflex Coating	10-Pack Al Reflex Coating	Wafer Al Reflex Coating
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Product Description

Value Line etched Silicon probes for imaging in Tapping Mode and non-contact mode, in air.

Specifications: 2.8 N/m, 75 kHz, 10 nm tip radius, no reflex coating.

- 10 probes per pack.
- Compatible with most commercially available AFMs.

Tip Specification

Geometry:	Standard (Steep)
Tip Height (h):	10 – 15 μm
Front Angle (FA):	25 ± 2.5°
Back Angle (BA):	15 ± 2.5°
Side Angle (SA):	22.5 ± 2.5°
Tip Radius (Nom):	10 nm
Tip Set Back (TSB)(Nom):	15 μm
Tip Set Back (TSB)(RNG):	5 - 25 μm

Cantilever Specification

Material:	0.01 - 0.025 Ωcm Antimony (n) doped Si
Geometry:	Rectangular
Cantilevers Number:	1
Cantilever Thickness (Nom):	2.75 μm
Cantilever Thickness (RNG):	2.0 - 3.5 μm

For more information email:
afmprobeorders@bruker.com or visit:

ValueAFMProbes.com